## Application/Control No. Applicant(s)/Patent Under Reexamination TERADA ET AL. Examiner Chieh M Fan Applicant(s)/Patent Under Reexamination TERADA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	К	US-			
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	М	US-			

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## **NON-PATENT DOCUMENTS**

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